8-BIT ADDRESSABLE LATCH

- SERIAL DATA INPUT - ACTIVE PARALLEL OUTPUT
- STORAGE REGISTER CAPABILITY - MASTER CLEAR
- CAN FUNCTION AS DEMULTIPLEXER
- STANDARDIZED SYMMETRICAL OUTPUT CHARACTERISTICS
- QUIESCENT CURRENT SPECIFIED TO 20V FOR HCC DEVICE
- 5V, 10V, AND 15V PARAMETRIC RATINGS
- INPUT CURRENT OF 100 nA AT 18V AND 25°C FOR HCC DEVICE
- 100% TESTED FOR QUIESCENT CURRENT
- MEETS ALL REQUIREMENTS OF JEDEC TENTATIVE STANDARD No. 13A, "STANDARD SPECIFICATIONS FOR DESCRIPTION OF "B" SERIES CMOS DEVICES"

The **HCC 4099B** (extended temperature range) and **HCF 4099B** (intermediate temperature range) are monolithic integrated circuits, available in 16-lead dual in-line plastic or ceramic package, ceramic flat package and plastic micropackage. The **HCC/HCF 4099B** 8-bit addressable latch is a serial-input, parallel-output storage register that can perform a variety of functions. Data are inputted to a particular bit in the latch when that bit is addressed (by means of inputs A0, A1, A2) and when WRITE DISABLE is at a low level. When WRITE DISABLE is high, data entry is inhibited; however, all 8 outputs can be continuously read independent of WRITE DISABLE and address inputs. A master RESET input is available, which resets all bits to a logic "0" level when RESET and WRITE DISABLE are at a high level. When RESET is at a high level, and WRITE DISABLE is at a low level, the latch acts as a 1-of-8 demultiplexer; the bit that is addressed has an active output which follows the data input, while all unaddressed bits are held to a logic "0" level.

ABSOLUTE MAXIMUM RATINGS

V_{DD}*	Supply voltage: **HCC** types	-0.5 to 20	V
	HCF types	-0.5 to 18	V
V_I	Input voltage	-0.5 to V_{DD} +0.5	V
I_I	DC input current (any one input)	± 10	mA
P_{tot}	Total power dissipation (per package)	200	mW
	Dissipation per output transistor for T_{op} = full package-temperature range	100	mW
T_{op}	Operating temperature: **HCC** types	-55 to 125	°C
	HCF types	-40 to 85	°C
T_{stg}	Storage temperature	-65 to 150	°C

* All voltage values are referred to V_{SS} pin voltage

ORDERING NUMBERS:

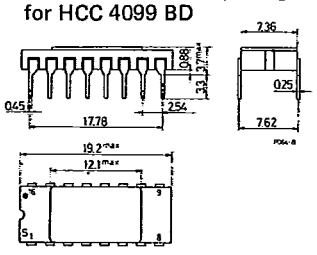
HCC 4099 BD for dual in-line ceramic package
HCC 4099 BF for dual in-line ceramic package, frit seal
HCC 4099 BK for ceramic flat package
HCF 4099 BE for dual in-line plastic package
HCF 4099 BF for dual in-line ceramic package, frit seal
HCF 4099 BM for plastic micropackage

HCC/HCF 4099B

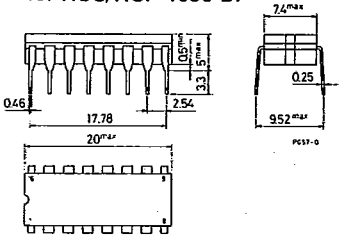
T-46-07-11

MECHANICAL DATA (dimensions in mm)

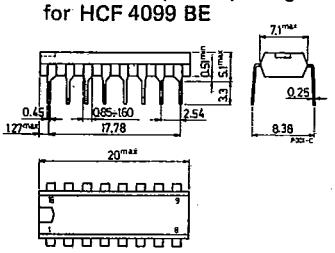
Dual in-line ceramic package for HCC 4099 BD



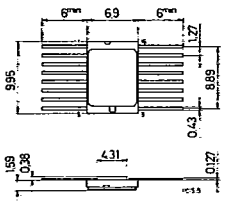
Dual in-line ceramic package for HCC/HCF 4099 BF



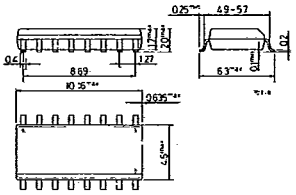
Dual in-line plastic package for HCF 4099 BE



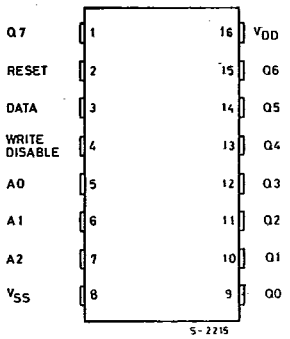
Ceramic flat package for HCC 4099 BK



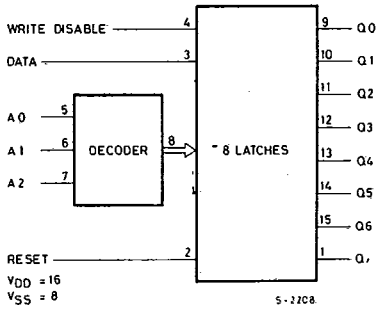
Plastic micropackage for HCF 4099 BM



CONNECTION DIAGRAM



FUNCTIONAL DIAGRAM

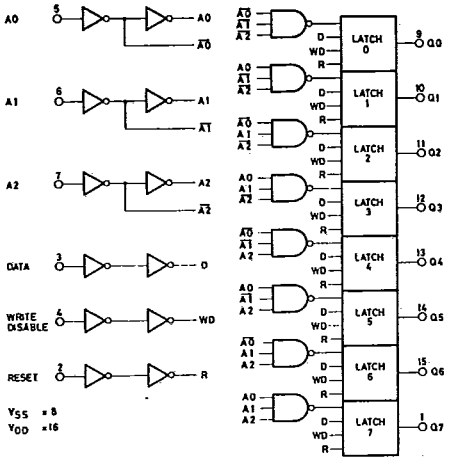


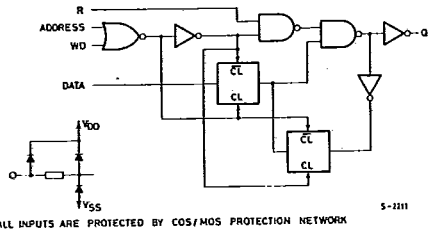
RECOMMENDED OPERATING CONDITIONS

V_{DD}	Supply voltage: **HCC** types	3 to 18	V
	HCF types	3 to 15	V
V_I	Input voltage	0 to V_{DD}	V
T_{op}	Operating temperature: **HCC** types	-55 to 125	°C
	HCF types	-40 to 85	°C

LOGIC DIAGRAM

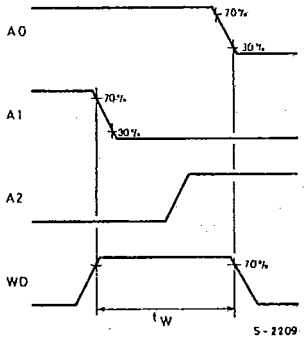
1 of 8 latches





ALL INPUTS ARE PROTECTED BY COS/MOS PROTECTION NETWORK

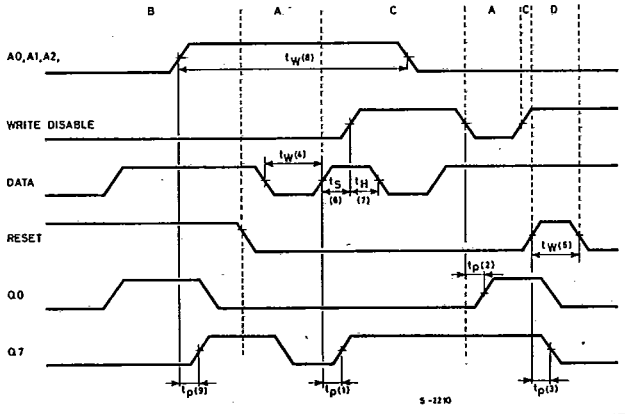
Definition of WRITE DISABLE ON time



TYPES	MODE SELECTION			
	WD	R	ADDRESSED LATCH	UNADDRESSED LATCH
A	0	0	Follows Data	Holds Previous State
B	0	1	Follows Data (Active High 8-Channel Demultiplexer)	Reset to "0"
C	1	0	Holds Previous State	
D	1	1	Reset to "0"	Reset to "0"

WD = WRITE DISABLE R = RESET

Master timing diagram



STATIC ELECTRICAL CHARACTERISTICS (over recommended operating conditions)

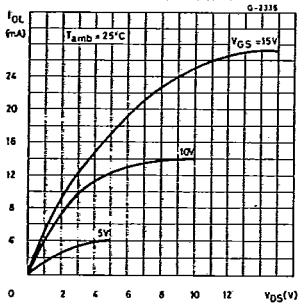
Parameter			Test conditions				Values							Unit
			V_I (V)	V_O (V)	$\|I_O\|$ (μA)	V_{DD} (V)	T_{Low}* Min.	T_{Low}* Max.	25°C Min.	25°C Typ.	25°C Max.	T_{High}* Min.	T_{High}* Max.	
I_L	Quiescent current	HCC types	0/ 5			5		5		0.04	5		150	μA
			0/10			10		10		0.04	10		300	
			0/15			15		20		0.04	20		600	
			0/20			20		100		0.08	100		3000	
		HCF types	0/ 5			5		20		0.04	20		150	
			0/10			10		40		0.04	40		300	
			0/15			15		80		0.04	80		600	
V_{OH}	Output high voltage		0/ 5		< 1	5	4.95		4.95			4.95		V
			0/10		< 1	10	9.95		9.95			9.95		
			0/15		< 1	15	14.95		14.95			14.95		
V_{OL}	Output low voltage		5/0		< 1	5		0.05			0.05		0.05	V
			10/0		< 1	10		0.05			0.05		0.05	
			15/0		< 1	15		0.05			0.05		0.05	
V_{IH}	Input high voltage			0.5/4.5	< 1	5	3.5		3.5			3.5		V
				1/9	< 1	10	7		7			7		
				1.5/13.5	< 1	15	11		11			11		
V_{IL}	Input low voltage			4.5/0.5	< 1	5		1.5			1.5		1.5	V
				9/1	< 1	10		3			3		3	
				13.5/1.5	< 1	15		4			4		4	
I_{OH}	Output drive current	HCC types	0/ 5	2.5		5	-2		-1.6	-3.2		-1.15		mA
			0/ 5	4.6		5	-0.64		-0.51	-1		-0.36		
			0/10	9.5		10	-1.6		-1.3	-2.6		-0.9		
			0/15	13.5		15	-4.2		-3.4	-6.8		-2.4		
		HCF types	0/ 5	2.5		5	-1.53		-1.36	-3.2		-1.1		
			0/ 5	4.6		5	-0.52		-0.44	-1		-0.36		
			0/10	9.5		10	-1.3		-1.1	-2.6		-0.9		
			0/15	13.5		15	-3.6		-3.0	-6.8		-2.4		
I_{OL}	Output sink current	HCC types	0/ 5	0.4		5	0.64		0.51	1		0.36		mA
			0/10	0.5		10	1.6		1.3	2.6		0.9		
			0/15	1.5		15	4.2		3.4	6.8		2.4		
		HCF types	0/ 5	0.4		5	0.52		0.44	1		0.36		
			0/10	0.5		10	1.3		1.1	2.6		0.9		
			0/15	1.5		15	3.6		3.0	6.8		2.4		
I_{IH}, I_{IL}	Input leakage current	HCC types	0/18	Any input		18		±0.1		$±10^{-5}$	±0.1		± 1	μA
		HCF types	0/15			15		±0.3		$±10^{-5}$	±0.3		± 1	
C_I	Input capacitance			Any input						5	7.5			pF

* T_{Low} = − 55°C for **HCC** device: −40°C for **HCF** device.
* T_{High} = +125°C for **HCC** device: +85°C for **HCF** device.
The Noise Margin for both "1" and "0" level is: 1V min. with V_{DD}= 5V
2V min. with V_{DD}= 10V
2.5V min. with V_{DD}= 15V

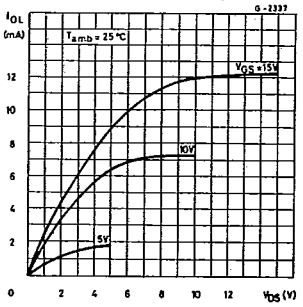
DYNAMIC ELECTRICAL CHARACTERISTICS (T_{amb}= 25°C, C_L= 50 pF, R_L= 200 kΩ, typical temperature coefficient for all V_{DD} values is 0.3%/°C, all input rise and fall times = 20 ns)

Parameter			Test conditions (see master timing diagram)	V_{DD}(V)	Values Min.	Typ.	Max.	Unit
t_{PLH}, t_{PHL}	Propagation delay time	Data to output	(1)	5		200	400	ns
				10		75	150	
				15		50	100	
		Write disable to output	(2)	5		200	400	
				10		80	160	
				15		60	120	
		Address to output	(9)	5		225	450	
				10		100	200	
				15		75	150	
t_{PHL}	Propagation delay time	Reset to output	(3)	5		175	350	
				10		80	160	
				15		65	130	
t_{THL}, t_{TLH}	Transition time	Any output		5		100	200	ns
				10		50	100	
				15		40	80	
t_W	Pulse width	Data	(4)	5	200	100		ns
				10	100	50		
				15	80	40		
		Address	(8)	5	400	200		
				10	200	100		
				15	125	65		
		Reset	(5)	5	150	75		
				10	75	40		
				15	50	25		
t_{setup}	Setup time	Data to write disable	(6)	5	100	50		ns
				10	50	25		
				15	35	20		
t_{hold}	Hold time	Data to write disable	(7)	5	150	75		ns
				10	75	40		
				15	50	25		

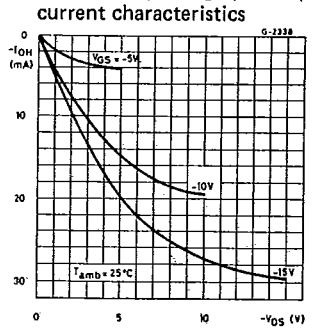
Typical output low (sink) current characteristics



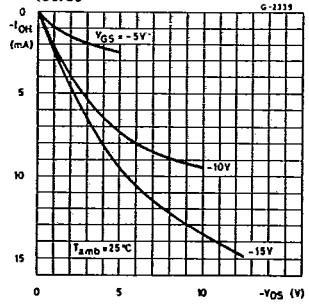
Minimum output low (sink) current characteristics



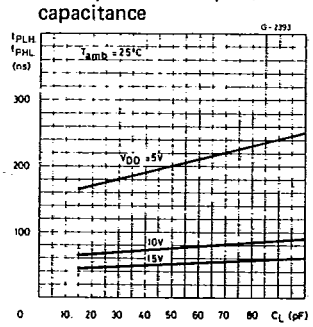
Typical output high (source) current characteristics



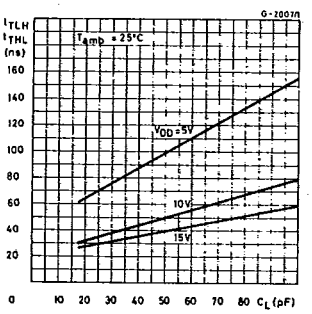
Minimum output high (source) current characteristics



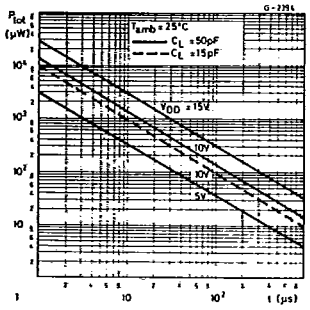
Typical propagation delay time (data to Qn) vs. load capacitance



Typical transition time vs. load capacitance

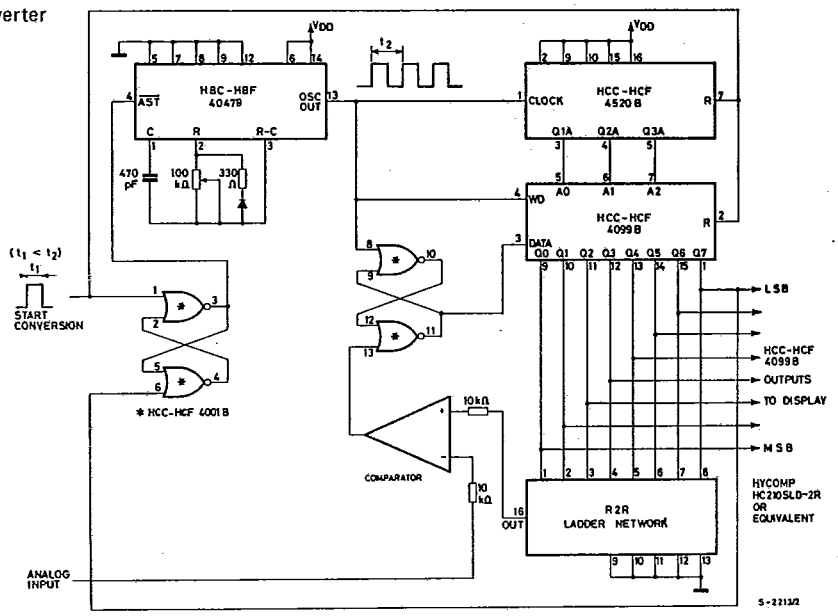


Typical dynamic power dissipation vs. address cycle time

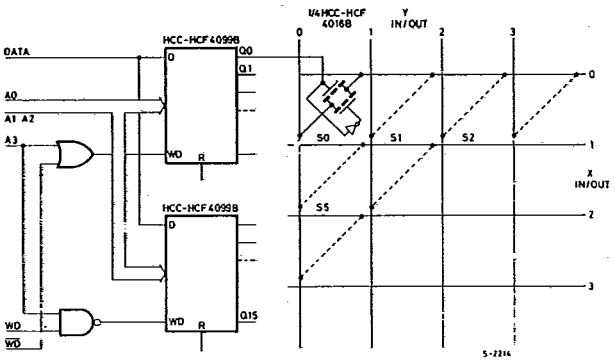


TYPICAL APPLICATIONS

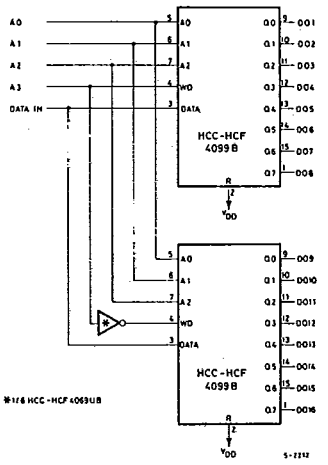
A/D converter



Multiple selection decoding - 4x4 crosspoint switch



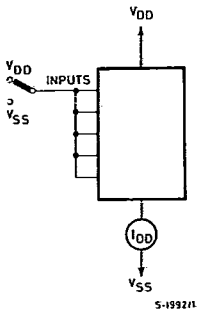
1 of 16 decoder/demultiplexer



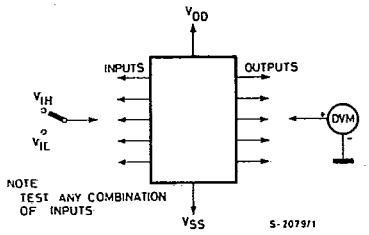
HCC/HCF 4099B

TEST CIRCUITS

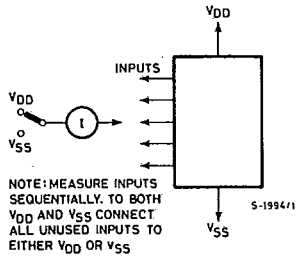
Quiescent device current

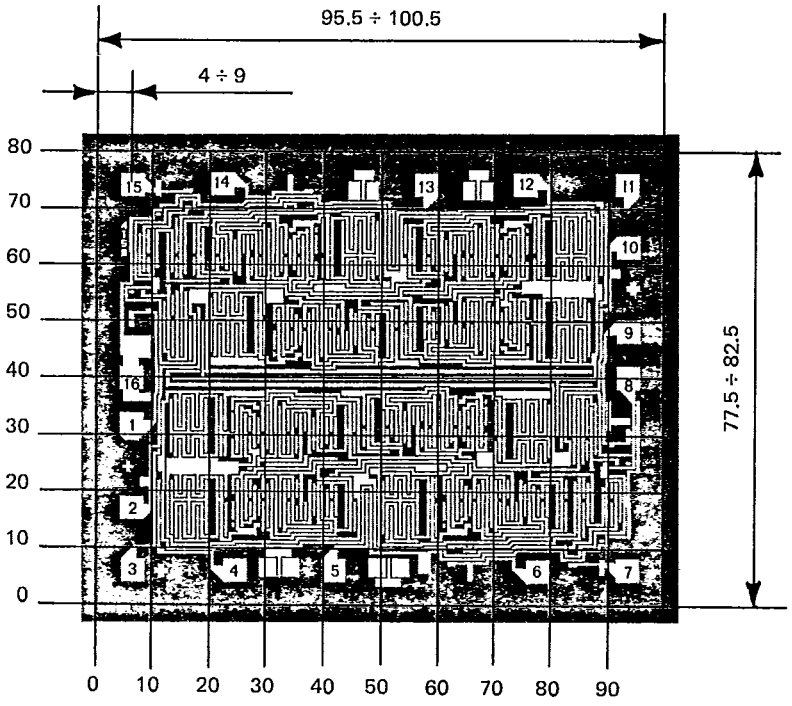


Input voltage

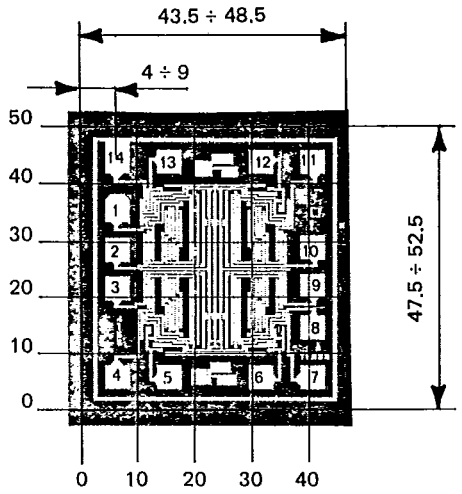


Input current




95.5 ÷ 100.5
4 ÷ 9
77.5 ÷ 82.5
80
70
60
50
40
30
20
10
0
0 10 20 30 40 50 60 70 80 90
15 14 13 12 11 10 9 8 16 1 2 3 4 5 6 7

4015B


43.5 ÷ 48.5
4 ÷ 9
47.5 ÷ 52.5
50
40
30
20
10
0
0 10 20 30 40
14 13 12 11 1 2 3 10 9 8 4 5 6 7

4016B